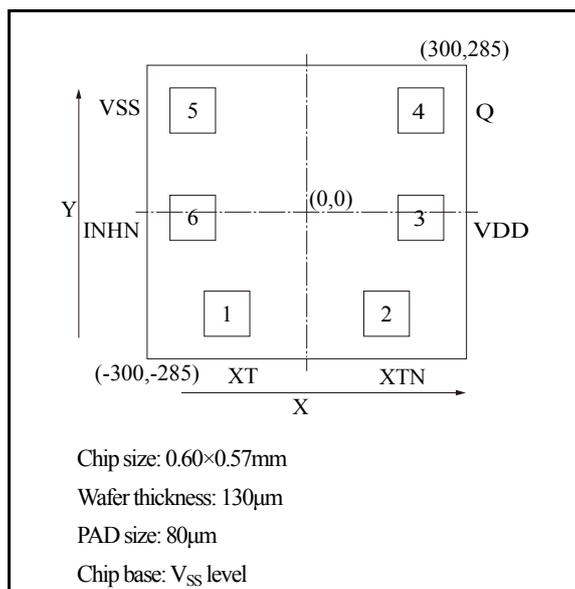




**PAD LAYOUT**

(Unit:  $\mu\text{m}$ )

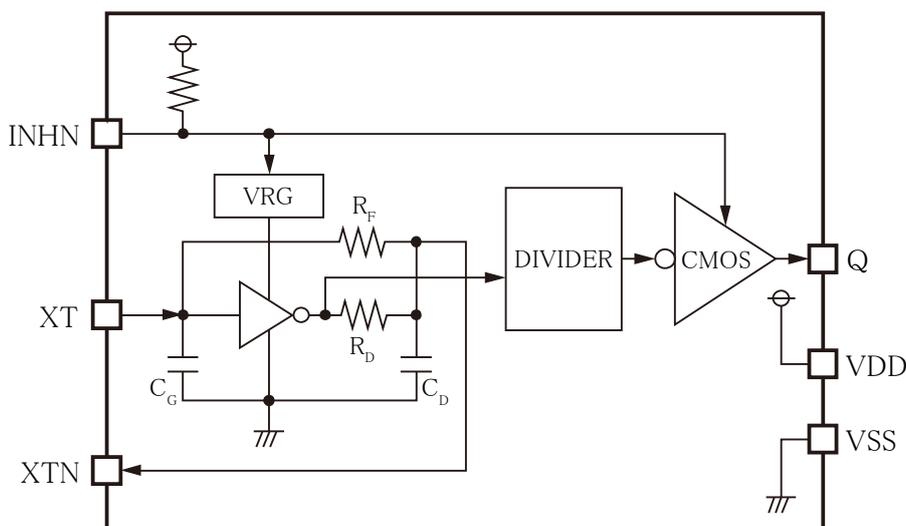


**PIN DESCRIPTION and PAD COORDINATES**

No.	Pin	I/O <sup>*1</sup>	Description	PAD coordinate [ $\mu\text{m}$ ]	
				X	Y
1	XT	I	Crystal connection pins Crystal is connected between XT and XTN.	-145.2	-193.5
2	XTN	O		145.2	-193.5
3	VDD	-	(+) supply voltage	208.5	-1.1
4	Q	O	Output one of $f_{\text{OSC}}$ , $f_{\text{OSC}}/2$ , $f_{\text{OSC}}/4$	208.5	193.5
5	VSS	-	(-) ground	-208.5	193.5
6	INH N	I	Input pin controlled output state (oscillator stops when LOW), power-saving pull-up resistor built-in	-208.5	-1.1

\*1. I: Input pin O: Output pin

**BLOCK DIAGRAM**



## SPECIFICATIONS

### Absolute Maximum Ratings

$V_{SS}=0V$

Parameter	Symbol	Condition	Rating	Unit
Supply voltage range <sup>*1</sup>	$V_{DD}$	Between VDD and VSS	-0.3 to +4.0	V
Input voltage range <sup>*1*2</sup>	$V_{IN}$	Input pins	-0.3 to $V_{DD}+0.3$	V
Output voltage range <sup>*1*2</sup>	$V_{OUT}$	Output pins	-0.3 to $V_{DD}+0.3$	V
Output current <sup>*3</sup>	$I_{OUT}$	Q pin	$\pm 20$	mA
Junction temperature <sup>*3</sup>	$T_j$		125	°C
Storage temperature range <sup>*4</sup>	$T_{STG}$	Wafer form	-65 to +125	°C

\*1. This parameter rating is the values that must never exceed even for a moment. This product may suffer breakdown if this parameter rating is exceeded.

Operation and characteristics are guaranteed only when the product is operated at recommended operating conditions.

\*2.  $V_{DD}$  is a  $V_{DD}$  value of recommended operating conditions.

\*3. Do not exceed the absolute maximum ratings. If they are exceeded, a characteristic and reliability will be degraded.

\*4. When stored in nitrogen or vacuum atmosphere applied to IC itself only (excluding packaging materials).

### Recommended Operating Conditions

$V_{SS}=0V$

Parameter	Symbol	Condition	Rating			Unit
			MIN	TYP	MAX	
Oscillator frequency <sup>*1</sup>	$f_{OSC}$	$V_{DD}=1.60$ to $3.63V$	20		40	MHz
Output frequency	$f_{OUT}$	$V_{DD}=1.60$ to $3.63V$ , $C_{LOUT} \leq 15pF$	5		40	MHz
Operating supply voltage	$V_{DD}$	Between VDD and VSS <sup>*2</sup>	1.60		3.63	V
Input voltage	$V_{IN}$	Input pins	$V_{SS}$		$V_{DD}$	V
Operating temperature	$T_a$		-40		+85	°C
Output load capacitance	$C_{LOUT}$	Q output			15	pF

\*1. The oscillation frequency is a yardstick value derived from the crystal used for NPC characteristics authentication. However, the oscillation frequency range is not guaranteed. Specifically, the characteristics can vary greatly due to crystal characteristics and mounting conditions, so the oscillation characteristics of components must be carefully evaluated.

\*2. Mount a ceramic chip capacitor that is larger than  $0.01\mu F$  proximal to IC (within approximately 3mm) between VDD and VSS in order to obtain stable operation of 5055A series. In addition, the wiring pattern between IC and capacitor should be as wide as possible.

Note. Since it may influence the reliability if it is used out of range of recommended operating conditions, this product should be used within this range.

## Electrical Characteristics

## DC Characteristics

$V_{DD}=1.60$  to  $3.63$  V,  $V_{SS}=0$  V,  $T_a=-40$  to  $+85$  °C unless otherwise noted.

Parameter	Symbol	Condition	Rating			Unit
			MIN	TYP	MAX	
Q pin HIGH-level output voltage	$V_{OH}$	measurement circuit 3, $I_{OH}=-3$ mA	$V_{DD}-0.4$		$V_{DD}$	V
Q pin LOW-level output voltage	$V_{OL}$	measurement circuit 3, $I_{OL}=3$ mA	0		0.4	V
INH pin HIGH-level input voltage	$V_{IH}$	measurement circuit 4	$0.7V_{DD}$			V
INH pin LOW-level input voltage	$V_{IL}$	measurement circuit 4			$0.3V_{DD}$	V
Q pin Output leakage current	$I_Z$	measurement circuit 5, INH=“Low”	$Q=V_{DD}$		10	$\mu$ A
			$Q=V_{SS}$	-10		
Current consumption *1	$I_{DD}$	5055A1( $f_{OSC}$ ), measurement circuit 1, no load, INH=“OPEN”, $f_{OSC}=40$ MHz, $f_{OUT}=40$ MHz	$V_{DD}=3.3$ V	1.1	1.75	mA
			$V_{DD}=2.5$ V	0.65	1.05	
			$V_{DD}=1.8$ V	0.45	0.7	
		5055A2( $f_{OSC}/2$ ), measurement circuit 1, no load, INH=“OPEN”, $f_{OSC}=40$ MHz, $f_{OUT}=20$ MHz	$V_{DD}=3.3$ V	0.85	1.45	mA
			$V_{DD}=2.5$ V	0.5	0.85	
			$V_{DD}=1.8$ V	0.35	0.6	
		5055A3( $f_{OSC}/4$ ), measurement circuit 1, no load, INH=“OPEN”, $f_{OSC}=40$ MHz, $f_{OUT}=10$ MHz	$V_{DD}=3.3$ V	0.8	1.35	mA
			$V_{DD}=2.5$ V	0.45	0.8	
			$V_{DD}=1.8$ V	0.3	0.55	
Standby current	$I_{ST}$	measurement circuit 1, INH=“Low”			10	$\mu$ A
INH pin pull-up resistance	$R_{PU1}$	measurement circuit 6	0.8	3	24	M $\Omega$
	$R_{PU2}$	measurement circuit 6	30	70	150	k $\Omega$
Oscillator feedback resistance	$R_f$		50	100	200	k $\Omega$
Oscillator capacitance	$C_G$	Design value (a monitor pattern on a wafer is tested),	1.6	2.0	2.4	pF
	$C_D$	Excluding parasitic capacitance.	2.4	3.0	3.6	

\*1. The consumption current  $I_{DD}(C_{LOUT})$  with a load capacitance ( $C_{LOUT}$ ) connected to the Q pin is given by the following equation, where  $I_{DD}$  is the no load consumption current and  $f_{OUT}$  is the output frequency.

$$I_{DD}(C_{LOUT})[\text{mA}] = I_{DD}[\text{mA}] + C_{LOUT}[\text{pF}] \times V_{DD}[\text{V}] \times f_{OUT}[\text{MHz}] \times 10^{-3}$$

AC Characteristics

$V_{DD} = 1.60$  to  $3.63V$ ,  $V_{SS} = 0V$ ,  $T_a = -40$  to  $+85^\circ C$  unless otherwise noted

Parameter	Symbol	Condition	Rating			Unit
			MIN	TYP	MAX	
Q pin Output rise time	$t_{r1}$	measurement circuit 1, $C_{LOUT}=15pF$ , $0.1V_{DD} \rightarrow 0.9V_{DD}$ , $V_{DD}=2.25$ to $3.63V$		2.0	6.0	ns
	$t_{r2}$	measurement circuit 1, $C_{LOUT}=15pF$ , $0.1V_{DD} \rightarrow 0.9V_{DD}$ , $V_{DD}=1.60$ to $2.25V$		3.0	8.0	
Q pin Output fall time	$t_{f1}$	measurement circuit 1, $C_{LOUT}=15pF$ , $0.9V_{DD} \rightarrow 0.1V_{DD}$ , $V_{DD}=2.25$ to $3.63V$		2.0	6.0	ns
	$t_{f2}$	measurement circuit 1, $C_{LOUT}=15pF$ , $0.9V_{DD} \rightarrow 0.1V_{DD}$ , $V_{DD}=1.60$ to $2.25V$		3.0	8.0	
Q pin Output duty cycle	DUTY	measurement circuit 1, $T_a=25^\circ C$ , $C_{LOUT}=15pF$	45	50	55	%
Q pin Output disable delay time	$t_{OD}$	measurement circuit 2, $T_a=25^\circ C$ , $C_{LOUT} \leq 15pF$			200	ns

Timing chart

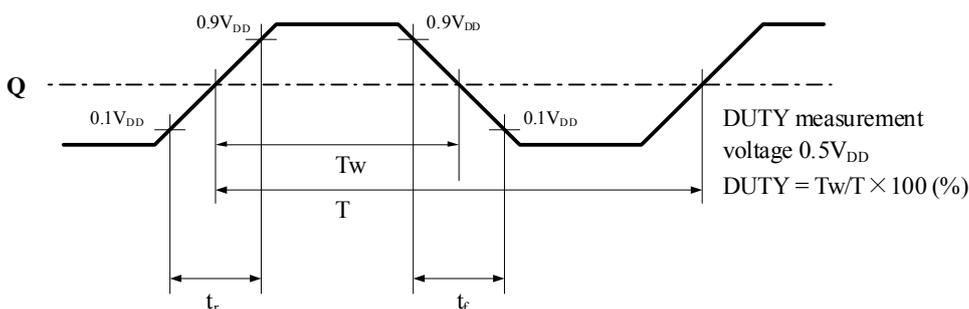
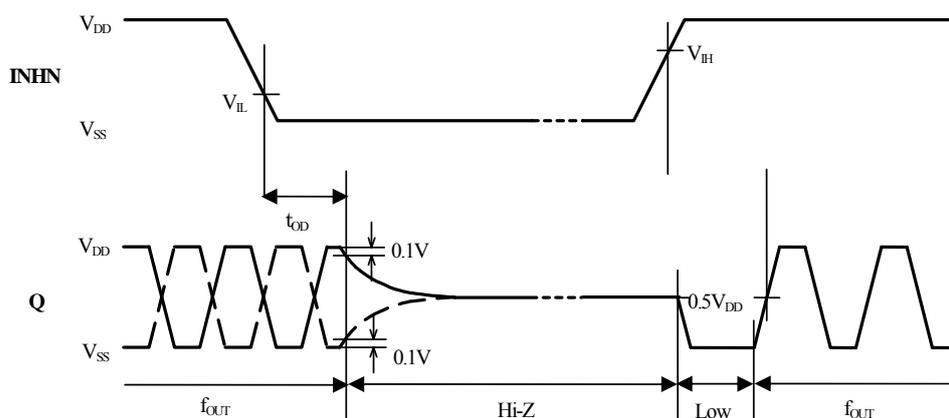


Figure 1. Output switching waveform



When INHN goes HIGH to LOW, the Q output becomes high impedance.

When INHN goes LOW to HIGH, the Q output goes LOW once and then becomes normal output operation after having detected oscillation signals.

Figure 2. Output disable and oscillation start timing chart

## FUNCTIONAL DESCRIPTION

### INH N Function

Q output is stopped and becomes high impedance.

INH N	Q	Oscillator
HIGH or Open	$f_{OUT}$	Operating
LOW	Hi-Z	Stopped

### Power Saving Pull-up Resistor

The INHN pin pull-up resistance changes its value to  $R_{PU1}$  or  $R_{PU2}$  in response to the input level (HIGH or LOW).

When INHN is tied to LOW level, the pull-up resistance becomes large ( $R_{PU1}$ ), thus reducing the current consumed by the resistance.

When INHN is left open circuit or tied to HIGH level, the pull-up resistance becomes small ( $R_{PU2}$ ), thus internal circuit of INHN becomes HIGH level.

Consequently, the IC is less susceptible to the effects of noise, helping to avoid problems such as the output stopping suddenly.

### Oscillation Detection Function

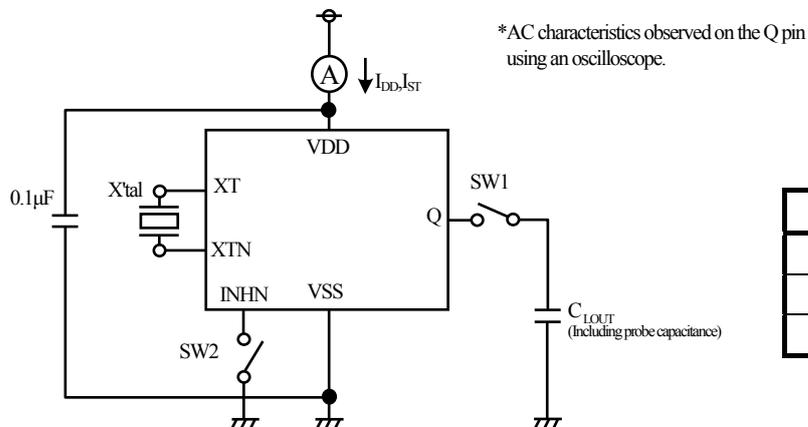
The 5055A series have an oscillation detection circuit.

The oscillation detection circuit disables the output until crystal oscillation becomes stable when oscillation circuit starts up. This function avoids the abnormal oscillation in the initial power up and in a reactivation by INHN.

## MEASUREMENT CIRCUITS

### MEASUREMENT CIRCUIT 1

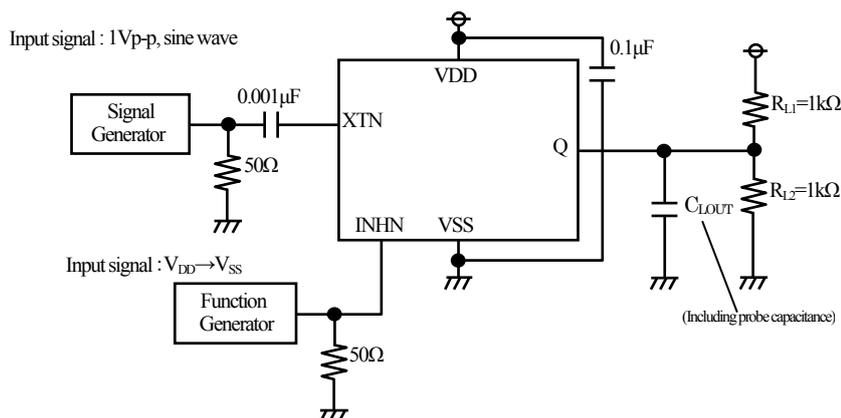
Measurement Parameter:  $I_{DD}$ ,  $I_{ST}$ , DUTY,  $t_p$ ,  $t_f$



Parameter	SW1	SW2
$I_{DD}$	OFF	OFF
$I_{ST}$	ON or OFF	ON
DUTY, $t_p$ , $t_f$	ON	OFF

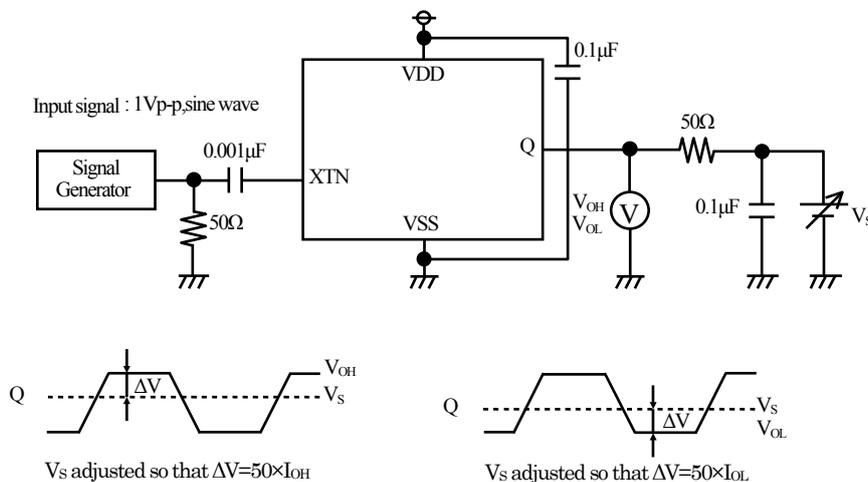
### MEASUREMENT CIRCUIT 2

Measurement Parameter:  $t_{OD}$



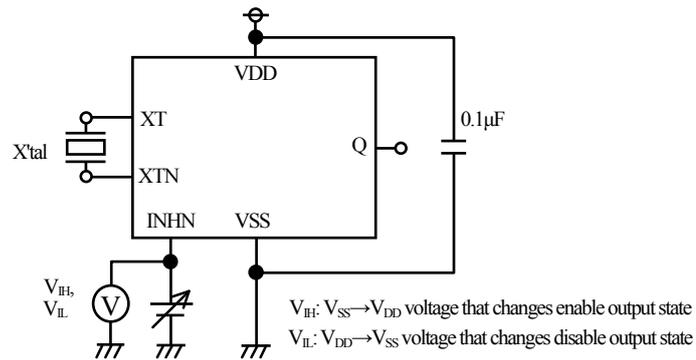
### MEASUREMENT CIRCUIT 3

Measurement Parameter:  $V_{OH}$ ,  $V_{OL}$



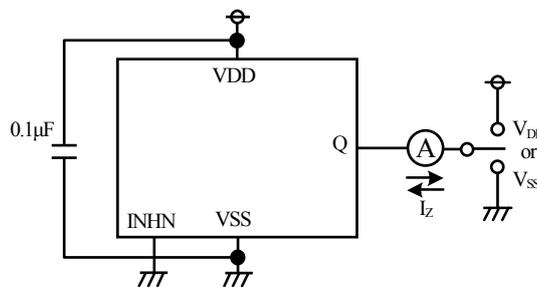
### MEASUREMENT CIRCUIT 4

Measurement Parameter:  $V_{IH}$ ,  $V_{IL}$



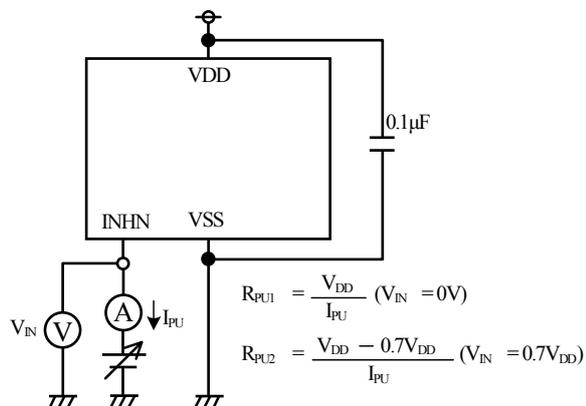
### MEASUREMENT CIRCUIT 5

Measurement Parameter:  $I_Z$



### MEASUREMENT CIRCUIT 6

Measurement Parameter:  $R_{PU1}$ ,  $R_{PU2}$



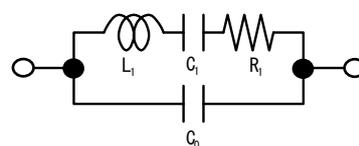
REFERENCE DATA

The following characteristics are measured using the crystal below. Note that the characteristics will vary with the crystal used.

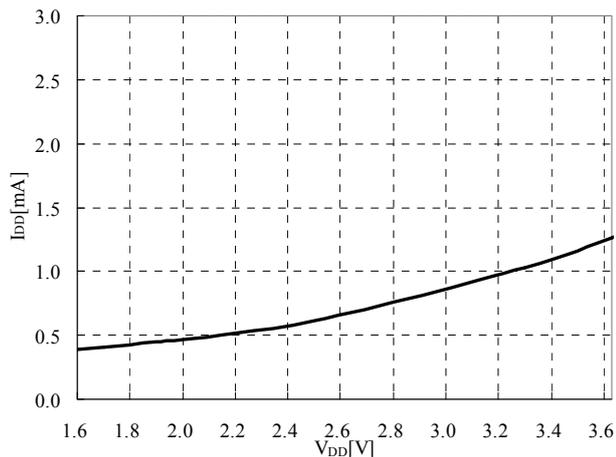
Crystal used for measurement

Parameter	27MHz	40MHz
$C_0$ (pF)	1.7	1.4
$R_1$ ( $\Omega$ )	8	8

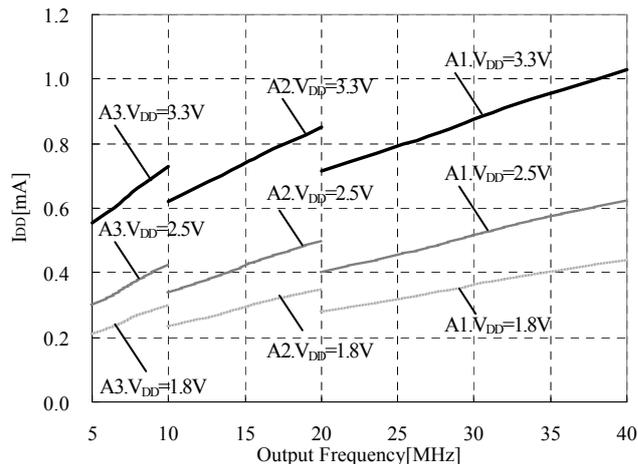
Crystal parameters



Current Consumption

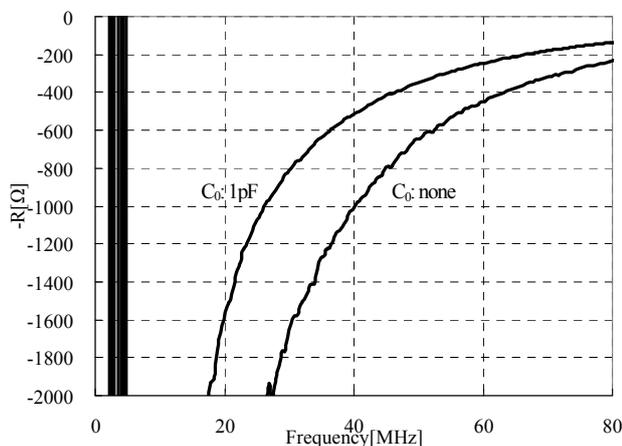


5055A1,  $f_{OSC}=40$ MHz,  $T_a$ : Room temperature,  $C_{LOAD}$ : none

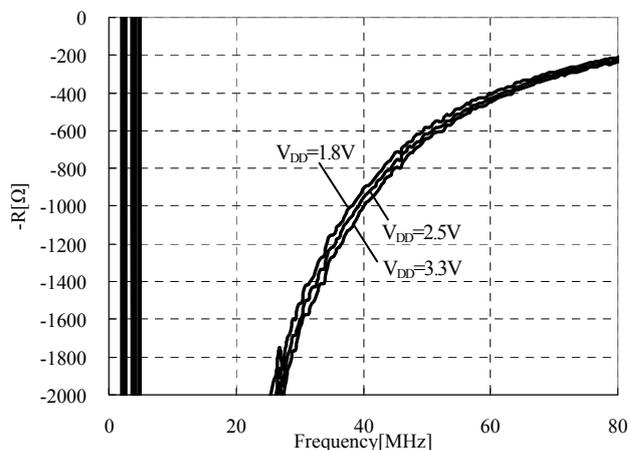


5055Ax,  $T_a$ : Room temperature,  $C_{LOAD}$ : none

Neagative Resistance



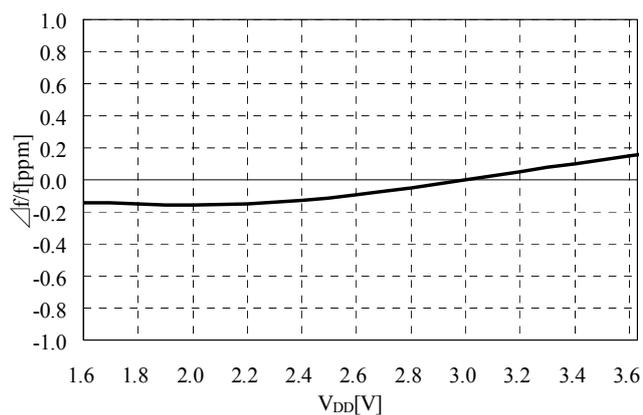
5055A1,  $V_{DD}=3.3$ V,  $T_a$ : Room temperature  
Measurement equipment: Agilent Impedance analyzer 4396B



5055A1,  $T_a$ : Room temperature,  $C_0$ : none

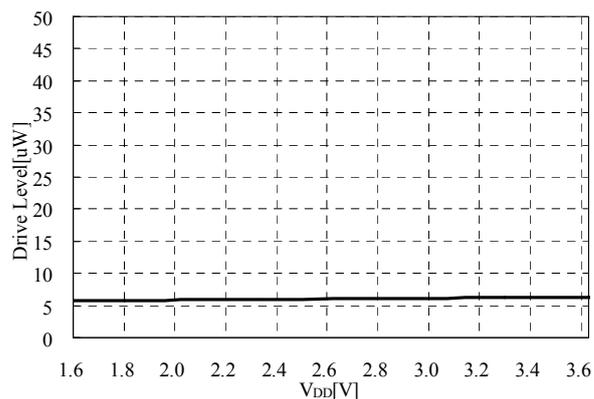
The figures show the measurement result of the crystal equivalent circuit  $C_0$  capacitance, connected between the XT and XTN pins. They were performed with Agilent 4396B using the NPC test jig. They may vary in a measurement jig, and measurement environment.

### Frequency Deviation by Voltage



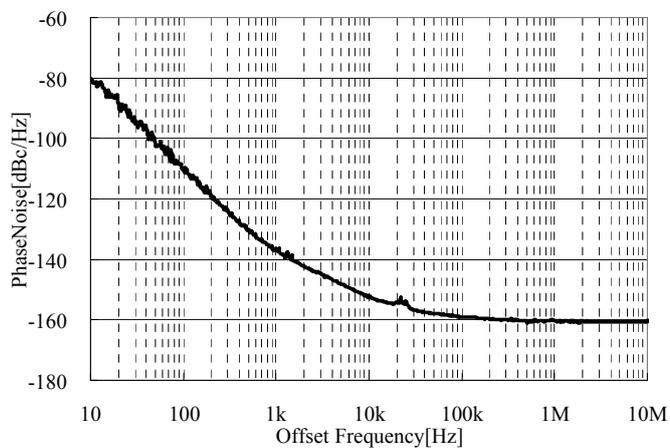
5055A1, f<sub>OSC</sub>=40MHz, T<sub>a</sub>: Room temperature, 3.0V std

### Drive Level



5055A1, f<sub>OSC</sub>=40MHz, T<sub>a</sub>: Room temperature

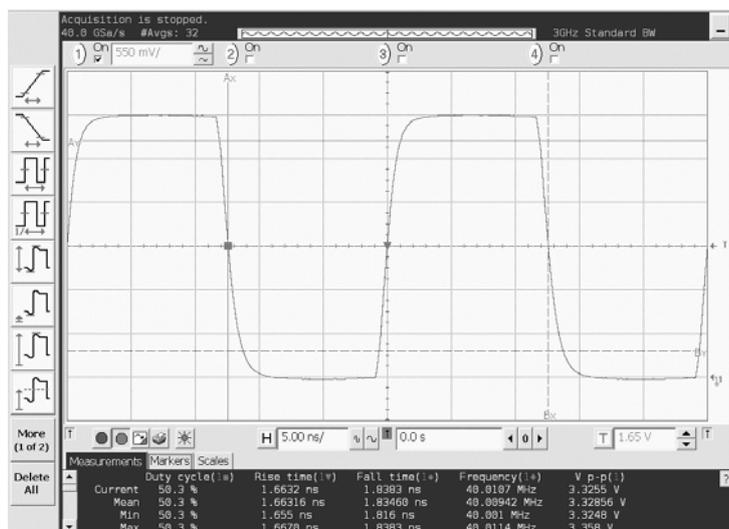
### Phase Noise



5055A1, f<sub>OSC</sub>=40MHz, V<sub>DD</sub>=3.3V, T<sub>a</sub>: Room temperature

Measurement equipment: Signal Source Analyzer Agilent E5052B

### Output Waveform



5055A1 version, V<sub>DD</sub>=3.3V, f<sub>OUT</sub>=40MHz, C<sub>LOUT</sub>=15pF, T<sub>a</sub>: Room temperature

Measurement equipment: Oscilloscope Agilent DSO80604B

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